

Description

The VSM60N04 uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

V_{DS} =40V,I_D =60A

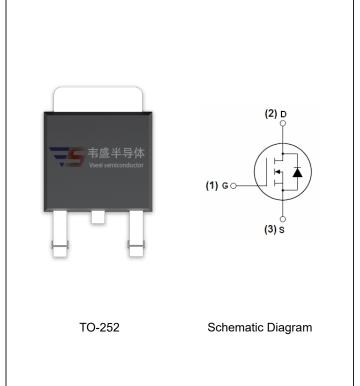
 $R_{DS(ON)}$ <8.5m Ω @ V_{GS} =10V

 $R_{DS(ON)}$ <18m Ω @ V_{GS} =4.5V

- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

Application

- Load switching
- Hard switched and high frequency circuits
- Uninterruptible power supply



Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
VSM60N04-T2	VSM60N04	TO-252	-	-	-

Absolute Maximum Ratings (T_c=25 ℃unless otherwise noted)

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	40	V	
Gate-Source Voltage	V _G s	±20	V	
Drain Current-Continuous	I _D	60	А	
Drain Current-Continuous(T _C =100 °C)	I _D (100°C)	42	А	
Pulsed Drain Current	I _{DM}	200	А	
Maximum Power Dissipation	P _D	65	W	
Derating factor		0.43	W/°C	
Single pulse avalanche energy (Note 5)	E _{AS}	400	mJ	
Operating Junction and Storage Temperature Range	T_{J} , T_{STG}	-55 To 175	$^{\circ}\mathbb{C}$	



Thermal Characteristic

Thermal Resistance, Junction-to-Case ^(Note 2)	$R_{ heta JC}$	2.3	°C/W	
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Electrical Characteristics (T_C=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA	40	45	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =40V,V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)	·		•	•		
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} ,I _D =250µA	1.2	1.6	2.0	V
Drain Source On State Registance	-	V _{GS} =10V, I _D =20A	-	7.3	8.5	mΩ
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =4.5V, I _D =20A		15	18	
Forward Transconductance	g FS	V _{DS} =10V,I _D =20A	15	-	-	S
Dynamic Characteristics (Note4)	·		•			
Input Capacitance	C _{lss}	\/ -20\/\/ -0\/	-	1800	-	PF
Output Capacitance	C _{oss}	- V _{DS} =20V,V _{GS} =0V, - F=1.0MHz	-	280	-	PF
Reverse Transfer Capacitance	C _{rss}	F-1.0IVITZ	-	190	-	PF
Switching Characteristics (Note 4)	·		•			
Turn-on Delay Time	t _{d(on)}	$V_{DD}=20V,I_{D}=2A,R_{L}=1\Omega$ $V_{GS}=10V,R_{G}=3\Omega$	-	6.4	-	nS
Turn-on Rise Time	t _r		-	17.2	-	nS
Turn-Off Delay Time	t _{d(off)}		-	29.6	-	nS
Turn-Off Fall Time	t _f		-	16.8	-	nS
Total Gate Charge	Qg	\/ -20\/ L -20 A	-	29		nC
Gate-Source Charge	Q _{gs}	$V_{DS}=20V,I_{D}=20A,$	-	4.5		nC
Gate-Drain Charge	Q _{gd}	V _{GS} =10V	-	6.4		nC
Drain-Source Diode Characteristics	·		•	•		
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =10A	-		1.2	V
Diode Forward Current (Note 2)	Is		-	-	60	Α
Reverse Recovery Time	t _{rr}	TJ = 25°C, IF = 20A	-	29	-	nS
Reverse Recovery Charge	Qrr	di/dt = 100A/µs ^(Note3)	-	26	-	nC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Notes

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board, $t \le 10$ sec.
- 3. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2%.
- **4.** Guaranteed by design, not subject to production
- **5.** E_{AS} condition : $Tj=25\,^{\circ}\mathrm{C}$, $V_{DD}=20V$, $V_{G}=10V$,L=1mH, $Rg=25\Omega$,

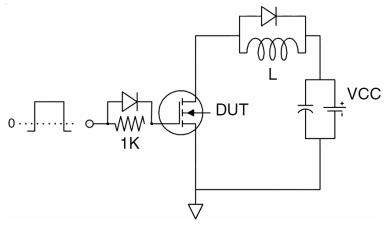


Test circuit

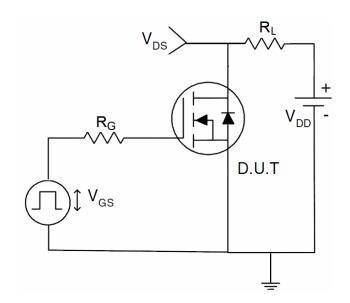
1) E_{AS} Test Circuit



2) Gate Charge Test Circuit



3) Switch Time Test Circuit





Typical Electrical and Thermal Characteristics (Curves)

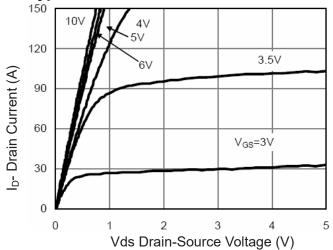


Figure 1 Output Characteristics

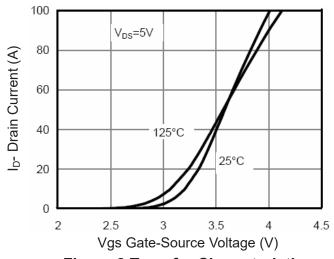


Figure 2 Transfer Characteristics

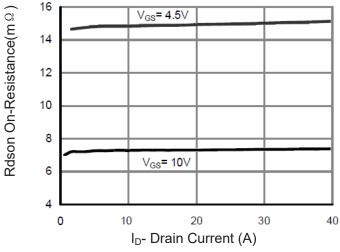


Figure 3 Rdson-Drain Current

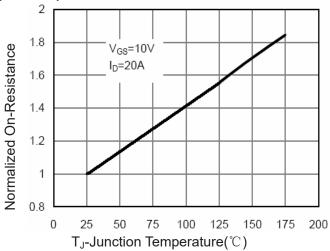


Figure 4 Rdson-JunctionTemperature

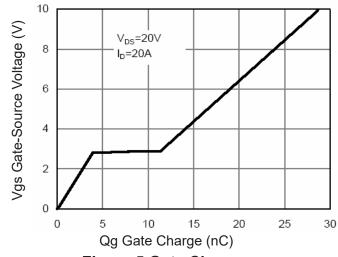


Figure 5 Gate Charge

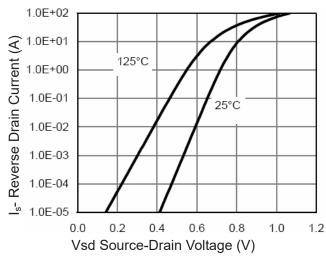


Figure 6 Source- Drain Diode Forward



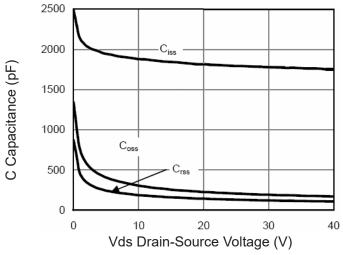
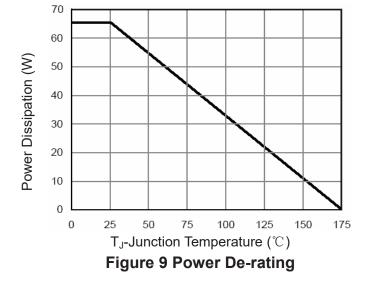


Figure 7 Capacitance vs Vds



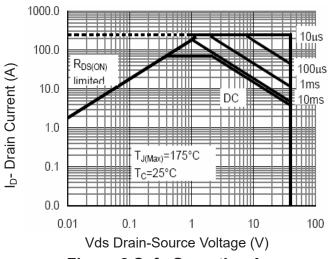


Figure 8 Safe Operation Area

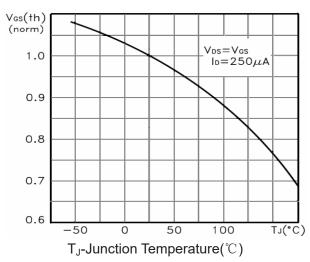


Figure 10 V_{GS(th)} vs Junction Temperature

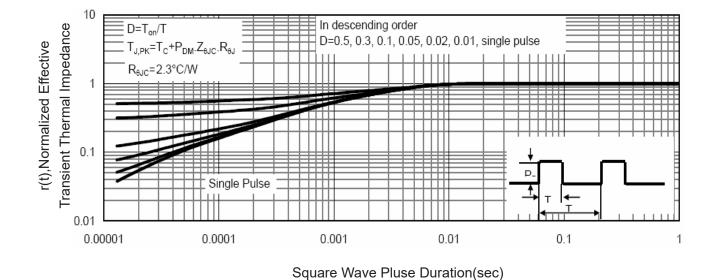


Figure 11 Normalized Maximum Transient Thermal Impedance